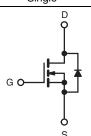


Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	50				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V	0.10			
Q _g (Max.) (nC)	24				
Q _{gs} (nC)	7.1				
Q _{gd} (nC)	7.1				
Configuration	Single				





N-Channel MOSFET

FEATURES

- For Automatic Insertion
- · Compact, End Stackable
- Fast Switching
- · Ease of Paralleling
- Excellent Temperature Stability
- Compliant to RoHS Directive 2002/95/EC





DESCRIPTION

The HVMDIP technology is the key to Vishay's advanced line of power MOSFET transistors. The efficient geometry and unique processing of the HVMDIP design achieves very low on-state resistance combined with high transconductance and extreme device ruggedness. HVMDIPs feature all of the established advantages of MOSFETs such as voltage control, very fast switching, ease of paralleling, and temperature stability of the electrical parameters.

The HVMDIP 4 pin, dual-in-line package brings the advantages of HVMDIPs to high volume applications where automatic PC board insertion is desireable, such as circuit boards for computers, printers, telecommunications equipment, and consumer products. Their compatibility with automatic insertion equipment, low-profile and end stackable features represent the stat-of-the-art in power device packaging.

ORDERING INFORMATION			
Package	HVMDIP		
Lead (Pb)-free	IRFD020PbF		
Lead (FD)-life	SiHFD020-E3		
SnPb	IRFD020		
OIII D	SiHFD020		

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage ^a			V _{DS}	50	V	
Gate-Source Voltage			V _{GS}	± 20	V	
Continuous Drain Current	\/ at 10.\/	T _C = 25 °C	- I _D	2.4	А	
	V _{GS} at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$		1.5		
Pulsed Drain Current ^b			I _{DM}	19		
Linear Derating Factor				0.0080	W/°C	
Inductive Current, Clamped	L = 1	L = 100 µH		19	А	
Unclamped Inductive Current (Avalanche Current) ^c			IL	2.2	A	
Maximum Power Dissipation	T _C = 25 °C		P_{D}	1.0	W	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		-	300 ^d	°C	

Notes

- a. $T_J = 25$ °C to 150 °C
- b. Repetitive rating; pulse width limited by maximum junction temperature.
- c. V_{DD} = 25 V, starting T_J = 25 °C, L = 100 μ H, R_q = 25 Ω
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFD020, SiHFD020

Vishay Siliconix



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R_{thJA}	-	120	°C/W	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static						•	,
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 250 μA	50	-	-	V
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 500	nA
7 0	I _{DSS}	V _{DS} = max. rating, V _{GS} = 0 V		-	-	250	μА
Zero Gate Voltage Drain Current		V _{DS} = max. ratio	$V_{DS} = \text{max. rating x } 0.8, V_{GS} = 0 \text{ V}, T_{C} = 125$		-	1000	
On-State Drain Current ^b	I _{D(on)}	V _{GS} = 10 V	$V_{DS} > I_{D(on)} \times R_{DS(on)} \max$.	2.4	-	-	Α
Drain-Source On-State Resistance ^b	R _{DS(on)}	V _{GS} = 10 V	I _D = 1.4 A	-	0.080	0.10	Ω
Forward Transconductance ^b	9fs	V _{DS}	= 20 V, I _D = 7.5 A	4.9	7.3	-	S
Dynamic							
Input Capacitance	C _{iss}		$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ f = 1.0 MHz		400	-	pF
Output Capacitance	C _{oss}				260	-	
Reverse Transfer Capacitance	C _{rss}				44	-	
Total Gate Charge	Qg			-	16	24	nC
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V	$I_D = 15 \text{ A},$ $V_{DS} = \text{max. rating x 0.8}$	-	4.7	7.1	
Gate-Drain Charge	Q_{gd}		V _{DS} = max. rating x 0.0		4.7	7.1	
Turn-On Delay Time	t _{d(on)}				8.7	13	ns ns
Rise Time	t _r	$V_{DD} = 25 \text{ V}, I_D = 15 \text{ A},$ $R_g = 18 \Omega, R_D = 1.7 \Omega$		-	55	83	
Turn-Off Delay Time	t _{d(off)}			-	16	24	
Fall Time	t _f				26	39	
Internal Drain Inductance	L _D	6 mm (0.25")	Between lead, 6 mm (0.25") from package and center of die contact		4.0	-	ьЫ
Internal Source Inductance	L _S				6.0	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	2.4	
Pulsed Diode Forward Current ^c	I _{SM}			-	-	19	A
Body Diode Voltage ^a	V _{SD}	T _C = 25 °C	T _C = 25 °C, I _S = 2.4 A, V _{GS} = 0 V		-	1.4	V
Body Diode Reverse Recovery Time	t _{rr}	T 05 00 1			130	310	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = 15 \text{A}, dI/dt = 100 \text{A/}\mu\text{s}$		0.17	0.34	0.85	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	ırn-on time is negligible (turn-	on is dor	ninated b	y L _S and	L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.
- c. V_{DD} = 25 V, starting T_J = 25 °C, L = 100 μH , R_g = 25 Ω





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

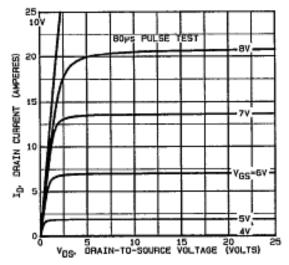


Fig. 1 - Typical Output Characteristics

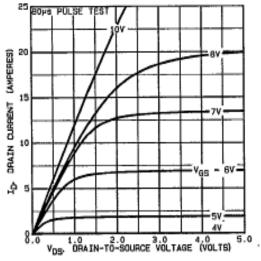


Fig. 2 - Typical Output Characteristics

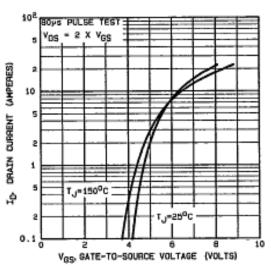


Fig. 3 - Typical Transfer Characteristics

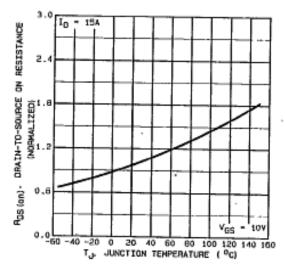


Fig. 4 - Normalized On-Resistance vs. Temperature



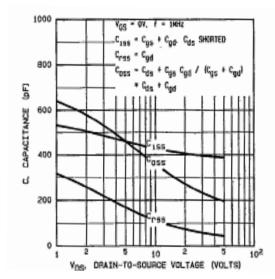


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

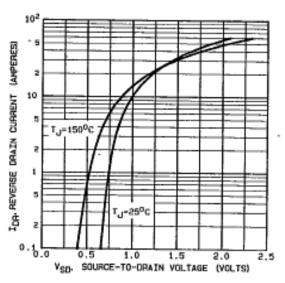


Fig. 7 - Typical Source-Drain Diode Forward Voltage

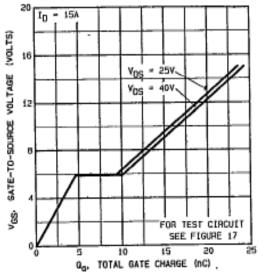


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

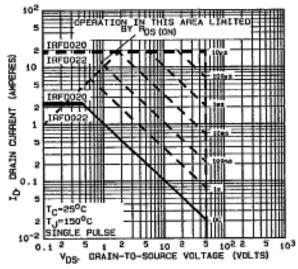


Fig. 8 - Maximum Safe Operating Area



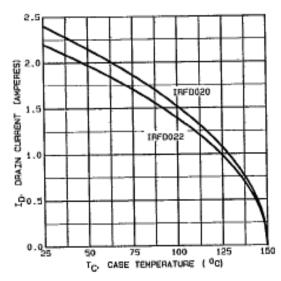


Fig. 9 - Maximum Drain Current vs. Ambient Temperature

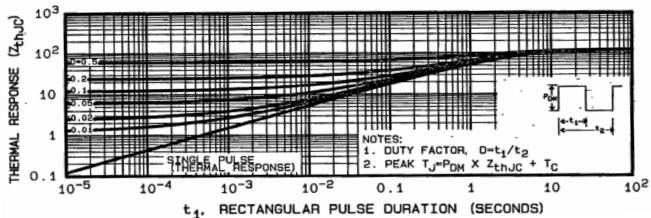


Fig. 10 - Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

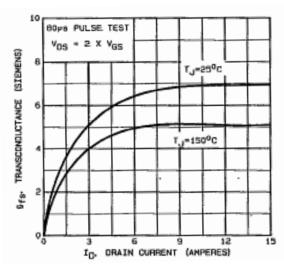


Fig. 11 - Typical Transconductance vs. Drain Current

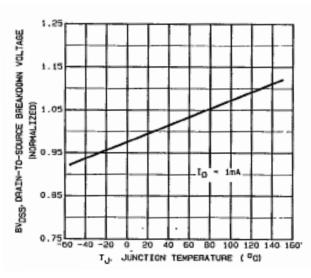


Fig. 12 - Breakdown Voltage vs. Temperature



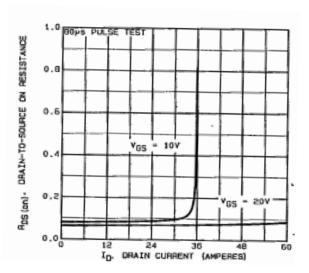


Fig. 13 - Typical on-Resistance vs. Drain Current

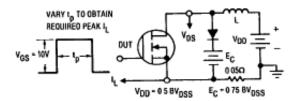


Fig. 14a - Clamped Inductive Test Circuit

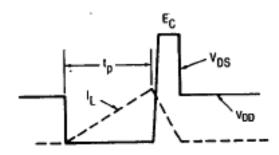


Fig. 14b - Clamped Inductive Waveforms

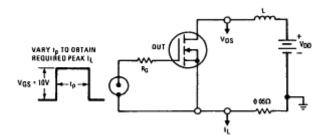


Fig. 15a - Unclamped Inductive Test Circuit

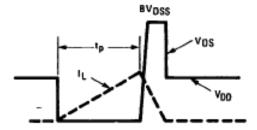


Fig. 15a - Unclamped Inductive Load Test Waveforms

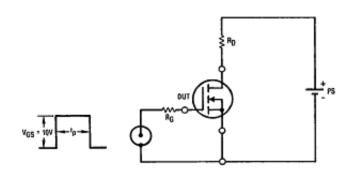


Fig. 16 - Switching Time Test Circuit

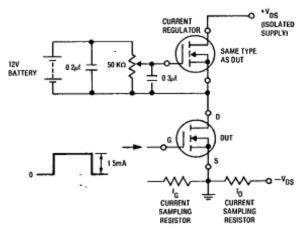
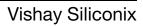
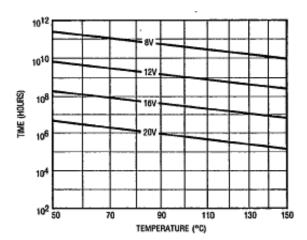


Fig. 17 - Gate Charge Test Circuit







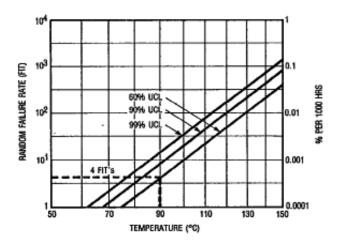


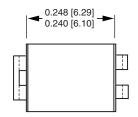
Fig. 18 - Typical Time to Accumulated 1 % Gate Failure

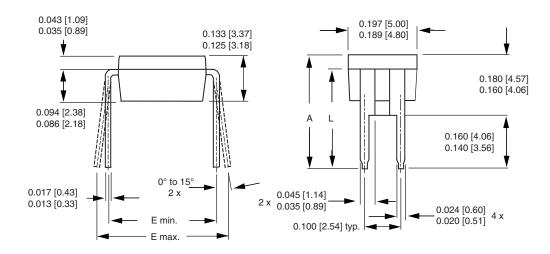
Fig. 19 - Typical High Temperature Reverse Bias (HTRB) Failure Rate

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HVM DIP (High voltage)





	INCHES		MILLIMETERS	
DIM.	MIN.	MAX.	MIN.	MAX.
A	0.310	0.330	7.87	8.38
Е	0.300	0.425	7.62	10.79
L	0.270	0.290	6.86	7.36

ECN: X10-0386-Rev. B, 06-Sep-10

DWG: 5974

Note

1. Package length does not include mold flash, protrusions or gate burrs. Package width does not include interlead flash or protrusions.

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